

BROADEN YOUR EXPERTISE:**REGISTER FOR A PROFESSIONAL DEVELOPMENT EVENT AT TMS2017**

INTRODUCTION TO ATOM PROBE TOMOGRAPHY COURSE

SUNDAY, FEBRUARY 26, 2017 • 1:00 P.M. TO 4:30 P.M.**Instructors**

David J. Larson, CAMECA Instruments Inc.; **Dieter Isheim**, Northwestern University;
Thomas F. Kelly, CAMECA Instruments Inc.; and **Michael Moody**, Oxford University
Organized by Wei Xiong, University of Pittsburgh, and Shuanglin Chen, CompuTherm LLC

Workshop Overview

Atom probe tomography (APT) is now one of the most powerful materials characterization techniques. This development has taken place so quickly that it is not described adequately in conventional textbooks, nor is it covered properly in the majority of existing undergraduate or graduate degree courses in materials science. Therefore, there is an urgent need of one professional development course of atom probe technique. It is expected that the course lecture will provide both beginners and experienced users of atom probe with valuable information regarding overview, technical details, and development progress. The course will be composed of four topics:

1. Basic Physical Principles of the Time of Flight Atom Probe, and Introduction to APT Instrumentation
2. Specimen Preparation Techniques, and How to Run APT Experiments
3. Methods for 3D Reconstruction of APT Data, and Data Analysis
4. Case Studies: Examples of the Use of APT for a Range of Materials Applications

Registration Fees

Register for this professional development event through the TMS 2017 Annual Meeting & Exhibition Registration Form.

	Through January 20, 2017	After January 20, 2017
Member	\$175	\$225
Nonmember	\$225	\$275
Student	\$75	\$125